CLAIMS

What is claimed is:

- 1 1. A method for fabricating a taper, comprising:
- 2 disposing a semiconductor waveguide on a substrate;
- forming a protective layer on the semiconductor waveguide;
- removing a portion of the protective layer to expose a portion of the semiconductor waveguide, the exposed portion of the semiconductor waveguide defining a footprint of the taper; and
- forming a semiconductor layer on the exposed portion of the semiconductor waveguide to form the taper, the taper having a termination end and a longitudinal axis, wherein the termination end has at least one unetched surface that is angled
- 10 relative to the longitudinal axis.
- 1 2. The method of claim 1 wherein the semiconductor waveguide is formed using 2 a silicon on insulator (SOI) wafer.
- 1 3. The method of claim 1 wherein the protective layer comprises an oxide.
- 1 4. The method of claim 1 wherein the semiconductor layer is formed using a
- 2 selective silicon epitaxy process.
- 1 5. The method of claim 4 wherein the semiconductor layer is formed into the

14

2 taper without etching the semiconductor layer.

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- 1 6. The method of claim 4 wherein the semiconductor layer has a sloped upper 2 surface.
- 7. The method of claim 6 wherein the sloped upper surface is formed without
 2 etching the semiconductor layer.
- 1 8. The method of claim 1 wherein forming the semiconductor layer comprises
- 2 depositing semiconductor material on the protective layer and the exposed portion of
- 3 the semiconductor waveguide, followed by chemical mechanical polishing to expose
- 4 the protective layer.
- 1 9. The method of claim 1 wherein a insulator layer is disposed beneath the
- 2 semiconductor waveguide.
- 1 10. An apparatus for propagating an optical signal, the apparatus comprising:
- 2 a semiconductor waveguide;
- a first insulating layer disposed on at least a first surface of the semiconductor
- 4 waveguide;
- 5 a second insulating layer disposed on at least a second surface of the
- 6 semiconductor waveguide; and
- a semiconductor taper disposed on a portion of the second surface of the
- 8 semiconductor waveguide, the semiconductor taper having a termination end and a
- 9 longitudinal axis, wherein the termination end has at least one unetched surface that
- is angled relative to the longitudinal axis.

- 1 11. The apparatus of claim 10 wherein the semiconductor taper is formed from
- 2 silicon epitaxially grown on a portion of the semiconductor waveguide left uncovered
- 3 by the second insulating layer.
- 1 12. The apparatus of claim 11 wherein the semiconductor taper has a sloped
- 2 surface that is parallel to the second surface of the semiconductor waveguide.
- 1 13. The apparatus of claim 12 wherein sloped surface of the semiconductor taper
- 2 is an unetched surface.
- 1 14. The apparatus of claim 10 wherein the taper includes a second end to be
- 2 coupled to an optical fiber.
- 1 15. The apparatus of claim 10 wherein the taper is formed from semiconductor
- 2 material on the second insulating layer and the portion of the second surface of the
- 3 semiconductor waveguide that has been planarized by chemical mechanical
- 4 polishing to expose the second insulating layer.
- 1 16. An integrated circuit comprising:
- 2 a semiconductor waveguide;
- a first insulating layer disposed on at least a first surface of the semiconductor
- 4 waveguide;
- a second insulating layer disposed on at least a second surface of the
- 6 semiconductor waveguide;
- a semiconductor taper disposed on a portion of the second surface of the
- 8 semiconductor waveguide, the semiconductor taper having a longitudinal axis, a

- 9 termination end and a wide end, the termination end having an unetched surface
- that is angled relative to the longitudinal axis, and the wide end to be coupled to an
- 11 optical fiber; and
- a protective layer formed to cover at least a portion of the semiconductor
- 13 layer.
- 1 17. The circuit of claim 16 wherein the semiconductor waveguide is formed from
- 2 silicon and the semiconductor taper is formed from silicon epitaxially grown on a
- 3 portion of the semiconductor waveguide left uncovered by the second insulating
- 4 layer.
- 1 18. The circuit of claim 17 wherein the semiconductor taper has a sloped surface
- that is parallel to the second surface of the semiconductor waveguide.
- 1 19. The circuit of claim 18 wherein sloped surface of the semiconductor taper is
- 2 an unetched surface.
- 1 20. The circuit of claim 16 wherein the taper is formed from semiconductor
- 2 material on the second insulating layer and the portion of the second surface of the
- 3 semiconductor waveguide that has been planarized by chemical mechanical
- 4 polishing to expose the second insulating layer.
- 1 21. A system comprising:
- 2 an optical signal source;
- an optical fiber, coupled to the optical signal source, to propagate an optical
- 4 signal; and

5	an integrated circuit that includes:
6	a semiconductor waveguide;
7 -	a first cladding layer disposed on at least a first surface of the
8 =	semiconductor waveguide;
9	a second cladding layer disposed on at least a second surface of the
10	semiconductor waveguide; and
11	a semiconductor taper disposed on a portion of the second surface of
12	the semiconductor waveguide, the semiconductor taper having a longitudinal axis, a
13	termination end and a wide end, the termination end having an unetched surface
14	that is angled relative to the longitudinal axis, and the wide end coupled to the

1 22. The system of claim 21 wherein the semiconductor waveguide is formed from 2 silicon and the semiconductor taper is formed from silicon epitaxially grown on a

15

optical fiber.

- 3 portion of the semiconductor waveguide left uncovered by the second cladding layer.
- 1 23. The system of claim 22 wherein the semiconductor taper has a sloped surface that is parallel to the second surface of the semiconductor waveguide.
- 1 24. The system of claim 23 wherein sloped surface of the semiconductor taper is 2 an unetched surface.